

Report No.: SZEM180300165802

No. 1 Workshop, M-10, Middle section, Science & Technology Park,

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SAR Evaluation Report

Application No.: SZEM1803001658CR

Applicant: Shenzhen DO Intelligent Technology Co., Ltd

Address of Applicant: 11th Floor, 3# Building, Guole Tech Park, Lirong Road, Dalang, Longhua

District, Shenzhen, China

Manufacturer: Shenzhen DO Intelligent Technology Co., Ltd

Address of Manufacturer: 11th Floor, 3# Building, Guole Tech Park, Lirong Road, Dalang, Longhua

District, Shenzhen, China

Factory: Shenzhen DO Intelligent Technology Co., Ltd

Address of Factory: 11th Floor, 3# Building, Guole Tech Park, Lirong Road, Dalang, Longhua

District, Shenzhen, China

Equipment Under Test (EUT):

EUT Name: Smart Bracelet

Model No.: ID115Plus Color HR

FCC ID: 2AHFTID115PLUSCOLOR

Standards: 47 CFR Part 1.1307

47 CFR Part 2.1093

KDB447498D01 General RF Exposure Guidance v06

Date of Receipt: 2018-03-06

Date of Test: 2018-03-08 to 2018-03-12

Date of Issue: 2018-03-13

Test Result : PASS*

* In the configuration tested, the EUT complied with the standards specified above.



EMC Laboratory Manager

The manufacturer should ensure that all products in series production are in conformity with the product sample detailed in this report. If the product in this report is used in any configuration other than that detailed in the report, the manufacturer must ensure the new system complies with all relevant standards. Any mention of SGS International Electrical Approvals or testing done by SGS International Electrical Approvals in connection with, distribution or use of the product described in this report must be approved by SGS International Electrical Approvals in writing.

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2 Version

Revision Record							
Version	Chapter	Date	Modifier	Remark			
01		2018-03-13		Original			

Authorized for issue by:		
	Peter. Goog	
	Peter Geng /Project Engineer	
	EvicFu	
	Eric Fu /Reviewer	



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4 General Information

4.1 General Description of EUT

Power supply:	DC 3.7V rechargeable battery which charged from USB port	
Frequency Range:	2402MHz to 2480MHz	
Bluetooth Version:	4.0 BLE	
Modulation Type:	GFSK	
Number of Channels:	40	
Antenna Type:	FPC antenna	
Antenna Gain:	-3.81dBi	



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4.2 Test Location

All tests were performed at:

SGS-CSTC Standards Technical Services Co., Ltd. Shenzhen Branch

No. 1 Workshop, M-10, Middle section, Science & Technology Park, Shenzhen, Guangdong, China 518057

Telephone: +86 (0) 755 2601 2053 Fax: +86 (0) 755 2671 0594

No tests were sub-contracted.

4.3 Test Facility

The test facility is recognized, certified, or accredited by the following organizations:

· CNAS (No. CNAS L2929)

CNAS has accredited SGS-CSTC Standards Technical Services Co., Ltd. Shenzhen Branch EMC Lab to ISO/IEC 17025:2005 General Requirements for the Competence of Testing and Calibration Laboratories (CNAS-CL01 Accreditation Criteria for the Competence of Testing and Calibration Laboratories) for the competence in the field of testing.

• A2LA (Certificate No. 3816.01)

SGS-CSTC Standards Technical Services Co., Ltd., Shenzhen EMC Laboratory is accredited by the American Association for Laboratory Accreditation(A2LA). Certificate No. 3816.01.

VCCI

The 3m Fully-anechoic chamber for above 1GHz, 10m Semi-anechoic chamber for below 1GHz, Shielded Room for Mains Port Conducted Interference Measurement and Telecommunication Port Conducted Interference Measurement of SGS-CSTC Standards Technical Services Co., Ltd. have been registered in accordance with the Regulations for Voluntary Control Measures with Registration No.: G-20026, R-14188, C-12383 and T-11153 respectively.

• FCC -Designation Number: CN1178

SGS-CSTC Standards Technical Services Co., Ltd., Shenzhen EMC Laboratory has been recognized as an accredited testing laboratory.

Designation Number: CN1178. Test Firm Registration Number: 406779.

Industry Canada (IC)

Two 3m Semi-anechoic chambers and the 10m Semi-anechoic chamber of SGS-CSTC Standards Technical Services Co., Ltd. Shenzhen Branch EMC Lab have been registered by Certification and Engineering Bureau of Industry Canada for radio equipment testing with Registration No.: 4620C-1, 4620C-2, 4620C-3.



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4.4 Deviation from Standards

None.

4.5 Abnormalities from Standard Conditions

None.

4.6 Other Information Requested by the Customer

None.



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5 SAR Evaluation

5.1 RF Exposure Compliance Requirement

5.1.1 Standard Requirement

According to KDB447498D01 General RF Exposure Guidance v06

4.3.1. Standalone SAR test exclusion considerations

Unless specifically required by the published RF exposure KDB procedures, standalone 1-g head or body and 10-g extremity SAR evaluation for general population exposure conditions, by measurement or numerical simulation, is not required when the corresponding SAR Exclusion Threshold condition, listed below, is satisfied.

5.1.2 Limits

The 1-g and 10-g SAR test exclusion thresholds for 100 MHz to 6 GHz at test separation distances ≤ 50 mm are determined by:

[(max. power of channel, including tune-up tolerance, mW)/(min. test separation distance, mm)] $\cdot [\sqrt{f(GHz)}] \le 3.0$ for 1-g SAR and ≤ 7.5 for 10-g extremity SAR, where

f(GHz) is the RF channel transmit frequency in GHz

Power and distance are rounded to the nearest mW and mm before calculation¹⁷

The result is rounded to one decimal place for comparison

The test exclusions are applicable only when the minimum test separation distance is \leq 50 mm and for transmission frequencies between 100 MHz and 6 GHz. When the minimum test separation distance is < 5 mm, a distance of 5 mm is applied to determine SAR test exclusion

5.1.3 EUT RF Exposure

The Max. power (including tune-up tolerance) is	-3.18 dBm on the lowest channel	2.402	GHz (*)
-3.18 dBm logarithmic terms convert to numeric re			
According to the formula. calculate the test exclu			
General RF Exposure = Max. Power of channel, including			
(min.test separation dist	$ance,mm) * \sqrt{f(GHz)}$		
General RF Exposure = (0.48 mW / 5 mm) x $\sqrt{2.402}$ GHz = 0.15			
SAR requirement:			
S = 3.0		(2)	
(1) < (2)			
So the SAR report is not required.			
(*) Max. power refer to Report No.:SZEM1803001	65801		

- End of the Report -